



**Computing Platform Service Partner**

# **RTC-1000AS**

## **Temp./Humidity Test Report**

**Report NO: 10E020020**



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**07/06/2010**

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**Date**

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**07/06/2010**

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**Date**

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## Testing Result

Num	Test item list	Result	Remark
1	Temp./humidity power on/off test	Pass	
2	Room temperature test	Pass	
3	Temperature rise test	Fail	
4	High temperature storage test	Pass	
5	High temperature operation test	Pass	
6	Low temperature storage test	Pass	
7	Low temperature operation test	Pass	
8	Humidity test	Pass	
9	Temperature shock operation test	Pass	
10	Temperature shock non-operation test	Pass	
11	Cold start and hot start test	Pass	

# Configuration of EUT

Num	Item	Spec
01.	<b>CPU:</b>	Intel Atom N270 / 1.6GHz / 0.9~1.2V / FSB: 533
02.	<b>PCBA</b>	RTC-1000A A1.0
03.	<b>BIOS</b>	RTC-1000A 1.0
04.	<b>Memory</b>	Team Group 1GB / Hynix HSPS1G831C-FP-S6 / DDR2 667
05.	<b>SATA HDD</b>	Western Digital 80GB / WD800BEVT
06.	<b>WLAN + BT Module</b>	AECO-AWM-S0021M
07.	<b>LCD</b>	CPT 10.2" LCD / CLAA102NA0ACW
08.	<b>LED Driving Board</b>	LITEMAX LID10B02
09.	<b>Touch Panel</b>	AMT 10454 4-wire, Analog Resistive
10.	<b>Modem</b>	QCOM-MA560-7 / Agere SV92A3 Chipset
11.	<b>Battery</b>	LI-ION Rechargeable Battery / H805084-3S DC11.1V / 4100mAh
12.	<b>AC Adapter</b>	LI SHIN 0335A2065 (Output: 20V / 3.25A)
13.	<b>AC Power Input</b>	110V / 60 Hz
14.	<b>Test Software</b>	Windows XP Embedded / Run Pass Mark Burn In Test 4.0 Pro

**Test Date:** 05-28~30-2010

**Test Model:** RTC-1000A A0.2

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference IEC 68-2-30 Testing procedures  
Test Db: Damp Heat Test  
Reference IEC 68-2-1 Testing procedures  
Test Ab: Cold Test

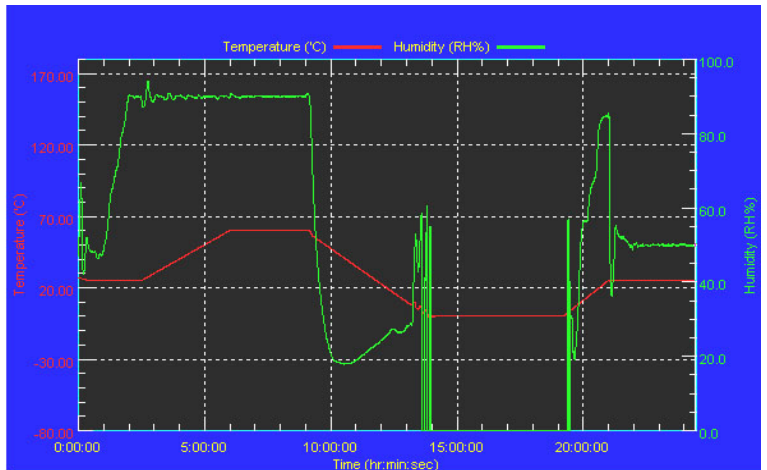
**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-B6T-150+LN2  
Date of Calibration: 04/01/10  
Serial Number: 6488KT

**Temperature & Humidity Power On/Off Test:**

**Testing Specification:**

Step	Temperature (°C)	Humidity (%RH)	Duration (HH:MM)
1	25	50	00:30
2	25	50	00:30
3	25	90	01:00
4	25	90	00:30
5	60	90	03:30
6	60	90	03:00
7	0	0	04:50
8	0	0	05:23
9	25	50	01:47
10	25	50	03:00

**Test Curve:**



**Test Result:**

**1. With Transcend 2GB / SEC K4T1G084QQ / DDR2-667 Memory**

No problem was found during the temperature & humidity power on/off test.

Test Method	Actual	Successful	Failure rate	On time	Off Time
Power On/Off	1389/times	1389/times	0%	33 Sec.	33 Sec.

Note: Failure rate need to under 0.2%.

**2. With Transcend 1GB / SEC K4T51083QC / DDR2-667 Memory**

No problem was found during the temperature & humidity power on/off test.

Test Method	Actual	Successful	Failure rate	On time	Off Time
Power On/Off	1431/times	1431/times	0%	30 Sec.	30 Sec.

Note: Failure rate need to under 0.2%.

**Test Date:** 07-02-2010

**Test Product:** RTC-1000AS

**Test Site:** AAEON QE Internal Lab.

**Temperature Measurement:**

40 Channel Thermal Recorder:  
YOKOGAWA Inc,  
Model: DA100-13-1D  
Date of Calibration: 12/08/09  
Serial Number: 12A323190

**Test Condition:**

Ambient temperature: 25dC  
Continuous running till thermal stability (within less than 1°C)

**Test Software:**

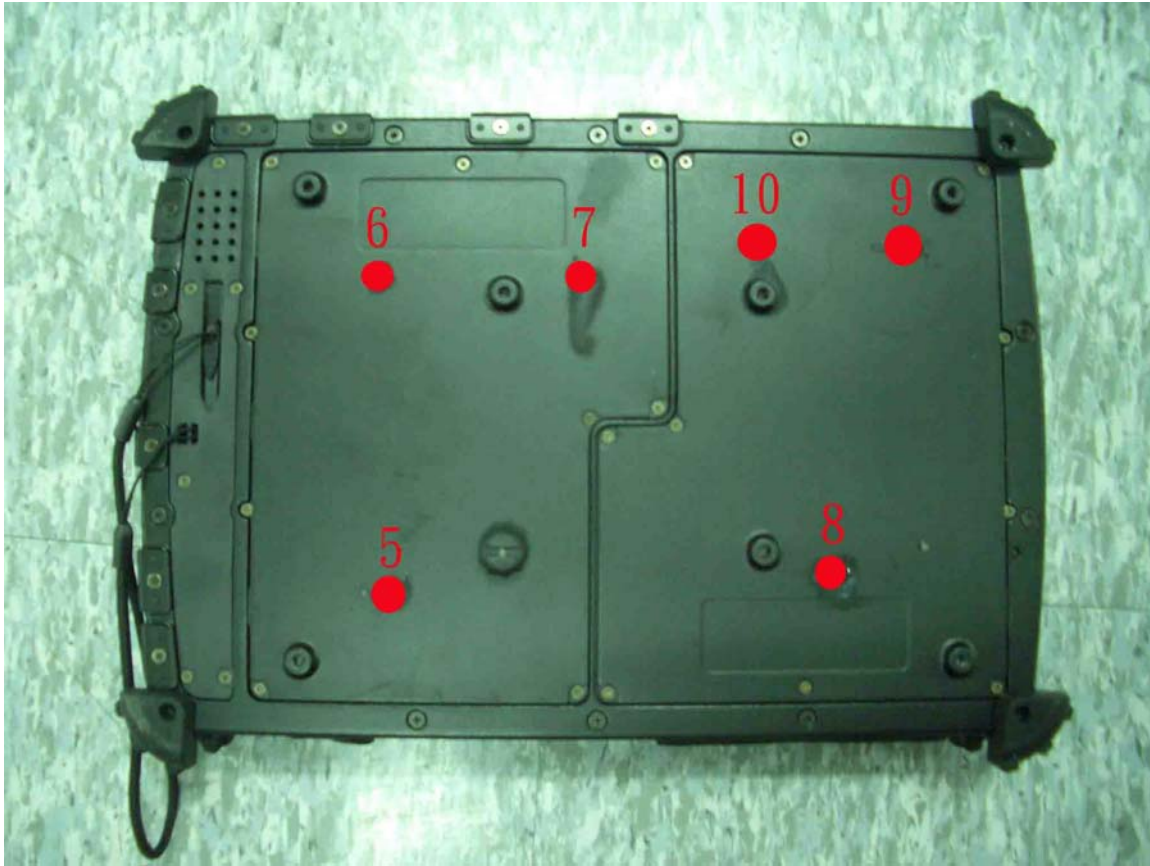
Windows XP Embedded / Run PassMark Burn In Test 4.0 Pro

**Terminal Recorder:**

Measuring Thermal Couple Position :



# Room Temperature test



**Thermal profile data:**

**RTC-1000AS**

Point	Temp. Stage(°C)	Spec	25
1. Point 1		$\Delta T$ $\leq 20$ $^{\circ}C$	39.2
2. Point 2			40.6
3. Point 3			38.2
4. Point 4			38.0
5. Point 5 - Bottom of Battery			39.6
6. Point 6 - Bottom of Battery			41.5
7. Point 7 - Bottom of RAM			42.7
8. Point 8 - Bottom of HDD			42.6
9. Point 9 - Bottom of FAN (CPU)			43.0
10. Point 10 - Bottom of FAN (NB)			43.8
Room Temperature			25.0
<b>Any Tm value showed in red words which meaning the value over the Tc degree C of this device specification.</b>			

**Sample Configuration & Quantity Under Test:**

Quantity: 1 (RTC-1000AS)

**Test Result:**

No problem was found during the room temperature operation test.

# Temperature rise test

**Test Date:** 07-01-2010

**Test Product:** RTC-1000AS

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference EN 61131-2(94), UL508 (94)

**Temperature Measurement:**

40 Channel Thermal Recorder:  
YOKOGAWA Inc,  
Model: DA100-13-1D  
Date of Calibration: 12/08/09  
Serial Number: 12A323190

**Test Condition:**

Ambient temperature: 35dC  
Continuous running till thermal stability (within less than 1°C)

**Test Software:**

Windows XP Embedded / Run PassMark Burn In Test 4.0 Pro

**Thermal profile data:**

**RTC-1000A**

Point	Temp. Stage(°C)	Spec	35	25
1. CPU		125	61.9	51.9
2. North Bridge		105	66.4	56.4
3. South Bridge		108	68.9	58.9
4. Clock Generator.IDT.9LPRS501PGLF		70	64.5	54.5
5. RAM ambient 1 - Between on board RAM & External RAM		85	66.6	56.6
6. RAM ambient 2 - Between External RAM & Bluetooth		85	66.2	56.2
7. WLAN		80	72.9	62.9
8. HDD - Between main board& HDD		60	61.4	51.4
9. Q103		150	78.6	68.6
10. Q99		150	79.1	69.1
11. L17		125	78.8	68.8
12. Q100		125	74.9	64.9
13. U46		125	70.2	60.2
14. Q91		125	71.9	61.9
15. U26		100	67.0	57.0
16. L20		125	89.7	79.7
17. U45		100	71.2	61.2
18. Q126		125	72.0	62.0
19. Q101		150	75.9	65.9
20. TC5		105	65.7	55.7
21. Chamber Air Temperature		N/A	35.1	25.1

**Any Tm value showed in red words which meaning the value over the Tc degree C of this device specification.**

**Sample Configuration & Quantity Under Test:**

Quantity: 1 (RTC-1000AS)

**Test Result:**

No problem was found during the temperature rise operation test. **But operation temperature of HDD was over the specification.**



**Test Date:** 05-31-2010 ~ 06-07-2010

**Test Product:** RTC-1000AS

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference MIL-STD 810F Method 501.4 High Temperature  
Procedure I - Storage

**Test Equipment:**

Programmable Temperature & Humidity Chamber

K.SON. INS. TECH. CORP.

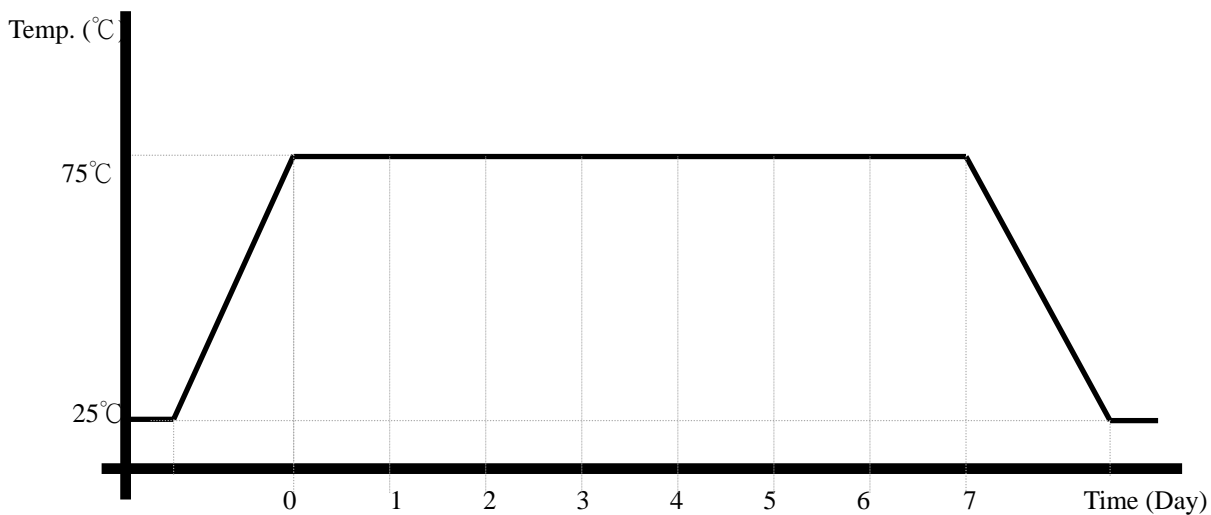
Model: THS-B6T-150+LN2

Date of Calibration: 04/01/10

Serial Number: 6488KT

**Testing Item:**

1. Test Temperature: 75°C
2. Test Time: 7days
3. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (RTC-1000AS)

**Test Result:**

No problem was found after the high temperature storage test.

**Test Date:** 06-11~17-2010

**Test Product:** RTC-1000AS

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference MIL-STD 810F Method 501.4 High Temperature  
Procedure II - Operation

**Test Equipment:**

Programmable Temperature & Humidity Chamber

K.SON. INS. TECH. CORP.

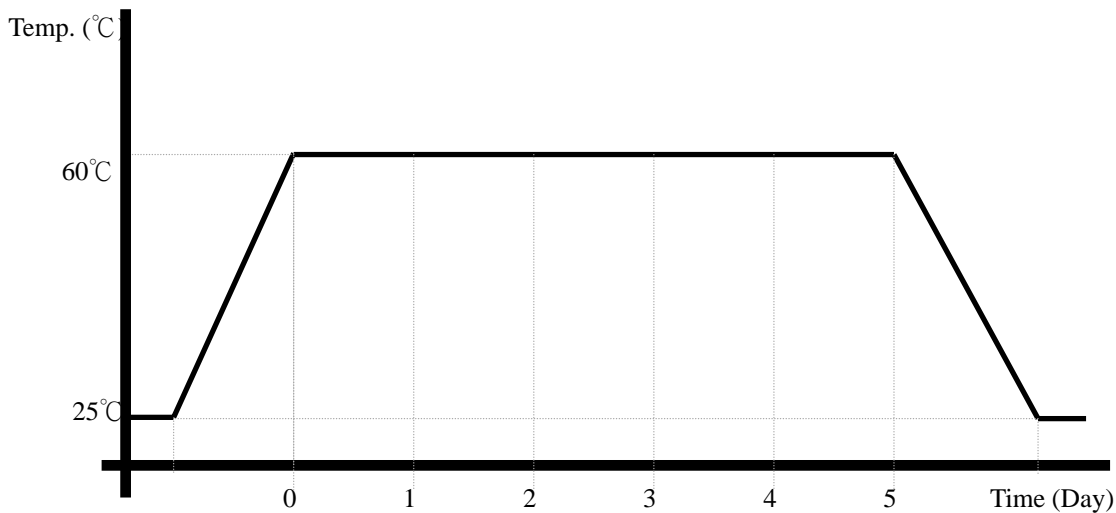
Model: THS-B6T-150+LN2

Date of Calibration: 04/01/10

Serial Number: 6488KT

**Testing Item:**

4. Test Temperature: 60°C
5. Test Time: 5days
6. Test Software: Windows XP Embedded / Run PassMark Burn In Test 4.0 Pro
7. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (RTC-1000AS)

**Test Result:**

No problem was found during the high temperature operation test.

**Test Date:** 06-28 ~ 29-2010

**Test Product:** RTC-1000AS

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference MIL-STD 810F Method 502.4 Low Temperature  
Procedure I - Storage

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-B6T-150+LN2  
Date of Calibration: 04/01/10  
Serial Number: 6488KT

**Testing Item:**

1. Test Temperature: -55°C
2. Test Times: 24Hrs
3. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (RTC-1000AS)

**Test Result:**

No problem was found after the low temperature storage test.

**Test Date:** 06-29~30-2010

**Test Product:** RTC-1000AS

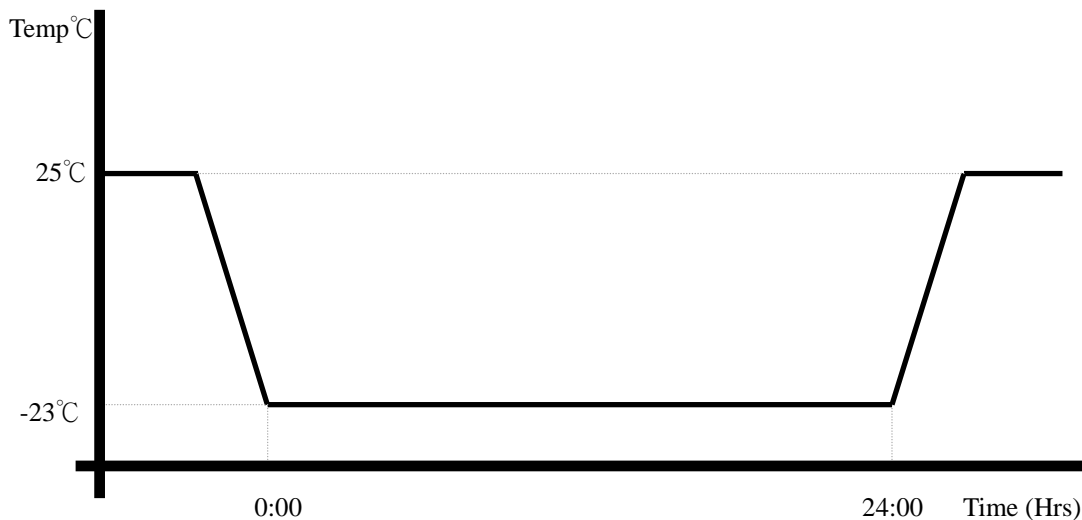
**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference MIL-STD 810F Method 501.4 High Temperature  
Procedure II - Operation

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-B6T-150+LN2  
Date of Calibration: 04/01/10  
Serial Number: 6488KT

**Testing Item:**

1. Test Temperature: -23°C
2. Test Times: 24Hrs
3. Test Software: Windows XP Embedded / Run PassMark Burn In Test 4.0 Pro
4. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**  
Quantity: 1 (RTC-1000AS)

**Test Result:**  
No problem was found during the low temperature operation test.

# Humidity test

**Test Date:** 06-17~27-2010

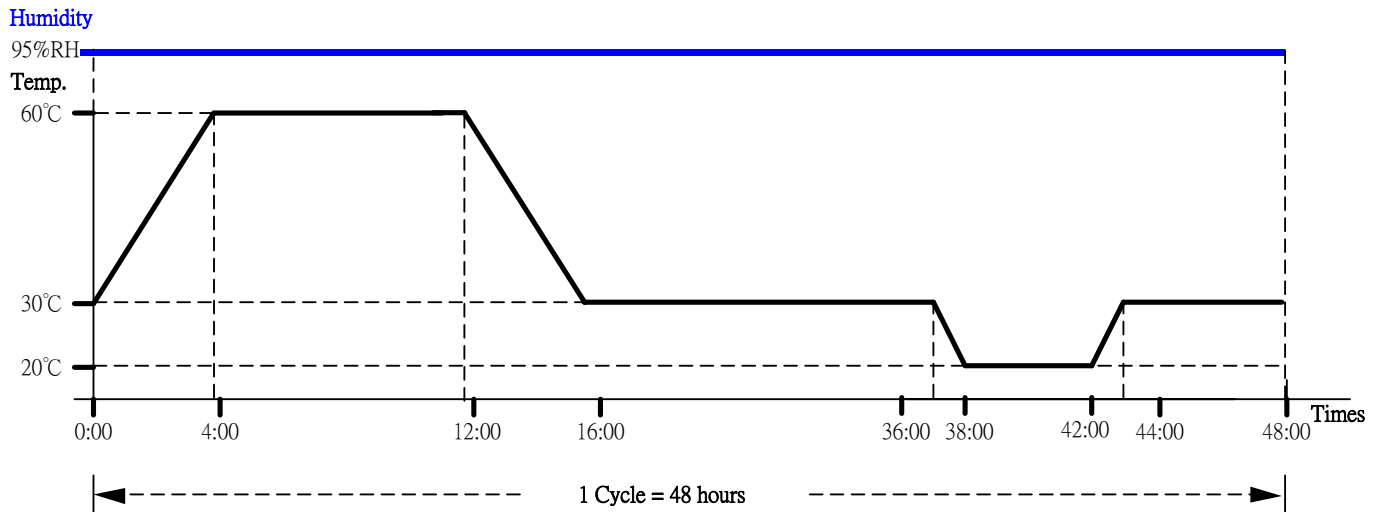
**Test Product:** RTC-1000AS

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference MIL-STD 810F Method 507.4 Testing procedures  
FIGURE 507.4-1. Aggravated temperature-humidity cycle

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-B6T-150+LN2  
Date of Calibration: 04/01/10  
Serial Number: 6488KT

- Test Condition:**
1. Test Humidity: 95%RH
  2. Test Temperature: 60°C / 30°C / 20°C
  3. Test Times: 48Hrs / Cycle
  4. Test Cycle: 5 Cycles
  5. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**  
Quantity: 1 (RTC-1000AS)

**Test Result:**  
No problem was found after the humidity storage test.

**Test Date:** 06-08~09-2010

**Test Product:** RTC-1000AS

**Test Site:** AAEON QE Internal Lab.

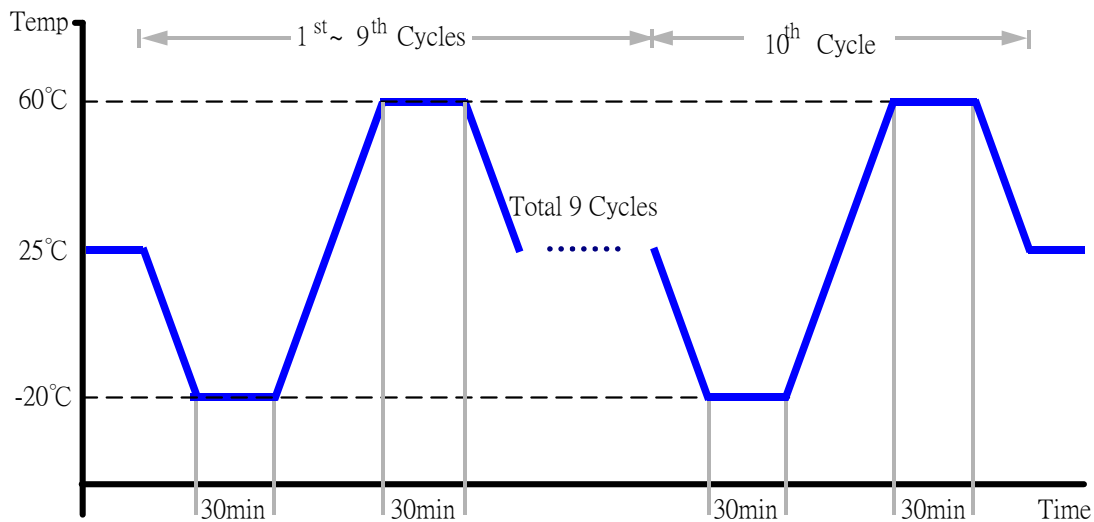
**Test Standard:** Reference MIL-STD 810F Method 503.4 Temperature Shock  
Procedure I - Shock from constant extreme temperatures

**Test Equipment:**

Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D7S-100+1 N2  
Date of Calibration: 12/08/09  
Serial Number: 3898

**Test Condition:**

1. Test Low Temperature: -20°C
2. Test High Temperature: 60°C
3. Test dwell time: 15min
4. Temperature slope: 5 min
5. Test cycle: 10 cycles
6. Test Software: Windows XP Embedded / Run PassMark Burn In Test 4.0 Pro
7. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (RTC-1000AS)

**Test Result:**

No problem was found during the variation temperature operation test.

**Test Date:** 06-09~11-2010

**Test Product:** RTC-1000AS

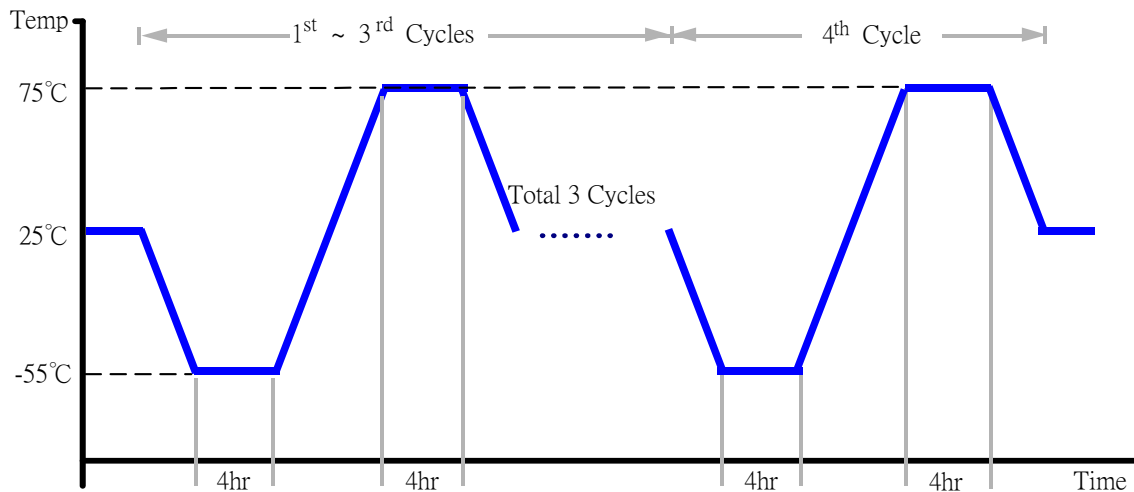
**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference MIL-STD 810F Method 503.4 Temperature Shock  
Procedure I - Shock from constant extreme temperatures

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-D7S-100+1 N2  
Date of Calibration: 12/08/09  
Serial Number: 3898

**Test Condition:**

1. Test Low Temperature: -55°C
2. Test High Temperature: 75°C
3. Test dwell time: 4Hrs
4. Temperature slope: 10 min
5. Test cycle: 4 cycles
6. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (RTC-1000AS)

**Test Result:**

No problem was found after the variation temperature non-operation test.

# Cold start and hot start test

**Test Date:** 06-07~08-2010

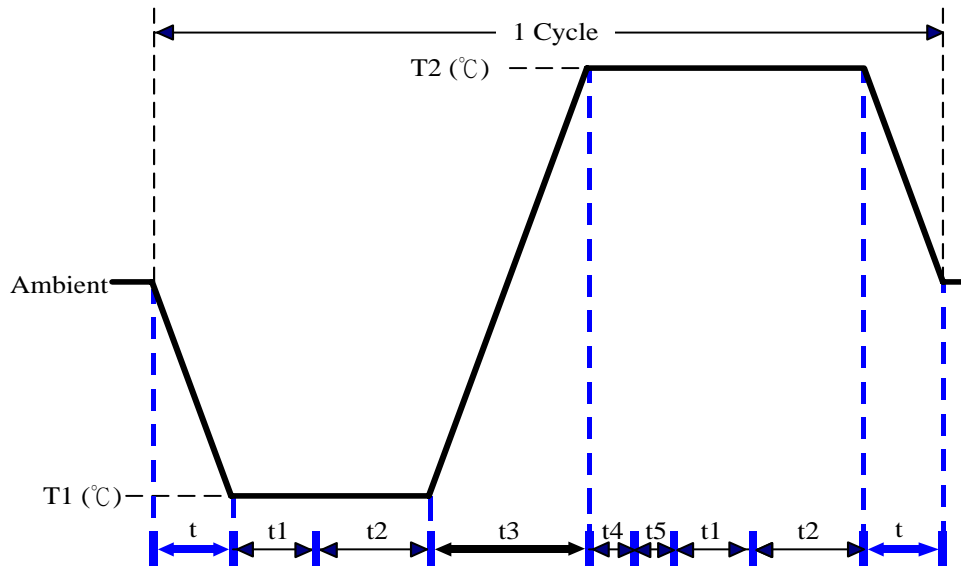
**Test Product:** RTC-1000AS

**Test Site:** AAEON QE Internal Lab.

**Test Standard:** Reference IEC 68-2-14 Testing procedures  
Test N: Change of temperature Test

**Test Equipment:**  
Programmable Temperature & Humidity Chamber  
K.SON. INS. TECH. CORP.  
Model: THS-B6T-150+LN2  
Date of Calibration: 04/01/10  
Serial Number: 6488KT

**Test Condition:**



Parameters	Description
T1	-5°C
T2	45°C
t1	1 hrs
t2	2 hrs
t4, t5	30 min
t, t3	2°C/min
n (Cycle)	1

t,t3 = temprature slope  
t, t1: Power Off  
t2: Power on/off test 5 times (on 2 min / off 5min)  
t3,t4: Run PassMark Burn In Test  
t5: Win XP Embedded Software restart test 2 times  
Test Software:Windows XP

**Test Result:**

- a. No problem was found during the cold start test.
- b. No problem was found during the hot start test.